MARCH 1988 - REVISED MARCH 1997

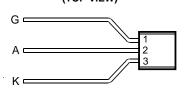
- 2 A Continuous On-State Current
- 15 A Surge-Current
- Glass Passivated Wafer
- 400 V to 600 V Off-State Voltage
- Max I_{GT} of 200 μA
- Package Options

PACKAGE	PACKING	PART # SUFFIX		
LP	Bulk	(None)		
LP with fomed leads	Tape and Reel	R		



MDC1AA

LP PACKAGE WITH FORMED LEADS (TOP VIEW)



MDC1AB

absolute maximum ratings over operating case temperature (unless otherwise noted)

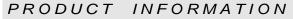
RATING			VALUE	UNIT
Panatitive nack off state valtage (and Nate 1)	TICP106D	V	400	V
Repetitive peak off-state voltage (see Note 1)	TICP106M	V _{DRM}	600	
	TICP106D	M	400	V
Repetitive peak reverse voltage	TICP106M	V _{RRM}	600	
Continuous on-state current at (or below) 85°C case temperature (see Note 2)		I _{T(RMS)}	2	А
Surge on-state current (see Note 3)		I _{TSM}	15	А
Peak positive gate current (pulse width \leq 300 µs)		I _{GM}	0.2	А
Average gate power dissipation (see Note 4)		P _{G(AV)}	0.3	W
Operating case temperature range		Т _С	-40 to +110	°C
Storage temperature range		T _{stg}	-40 to +125	°C
Lead temperature 3.2 mm from case for 10 seconds		ΤL	230	°C

NOTES: 1. These values apply when the gate-cathode resistance R_{GK} = 1 k\Omega.

2. These values apply for continuous dc operation with resistive load. Above 85°C derate linearly to zero at 110°C .

3. This value applies for one 50 Hz half-sine-wave when the device is operating at (or below) the rated value of peak reverse voltage and on-state current. Surge may be repeated after the device has returned to original thermal equilibrium.

4. This value applies for a maximum averaging time of 20 ms.



Information is current as of publication date. Products conform to specifications in accordance with the terms of Power Innovations standard warranty. Production processing does not necessarily include testing of all parameters.



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electrical characteristics at 25°C case temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIC	DNS	MIN	TYP	MAX	UNIT
I _{DRM}	Repetitive peak off-state current	$V_D = rated V_{DRM}$	R_{GK} = 1 k Ω				20	μΑ
I _{RRM}	Repetitive peak reverse current	V_R = rated V_{RRM}	$I_{G} = 0$				200	μΑ
I _{GT}	Gate trigger current	V _{AA} = 6 V	R _L = 100 Ω	t _{p(g)} ≥ 20 μs		60	200	μΑ
V _{GT}	Gate trigger voltage	V _{AA} = 6 V	R _L = 100 Ω R _{GK} = 1 kΩ	$t_{p(g)} \ge 20 \ \mu s$	0.4		1	V
Ι _Η	Holding current	V _{AA} = 6 V	$R_{GK} = 1 \ k\Omega$	Initiating I _T = 10 mA			5	mA
V_{TM}	Peak on-state voltage	I _{TM} = 1 A	(see Note 5)				1.5	V

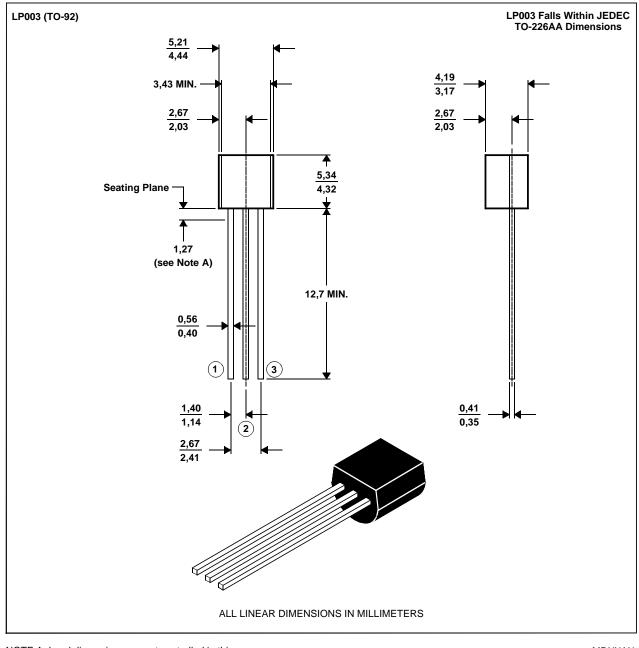
NOTE 5: This parameter must be measured using pulse techniques, t_p = 1 ms, duty cycle ≤ 2 %. Voltage sensing-contacts, separate from the current carrying contacts, are located within 3.2 mm from the device body.

MECHANICAL DATA

LP003 (TO-92)

3-pin cylindical plastic package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTE A: Lead dimensions are not controlled in this area.

MDXXAX





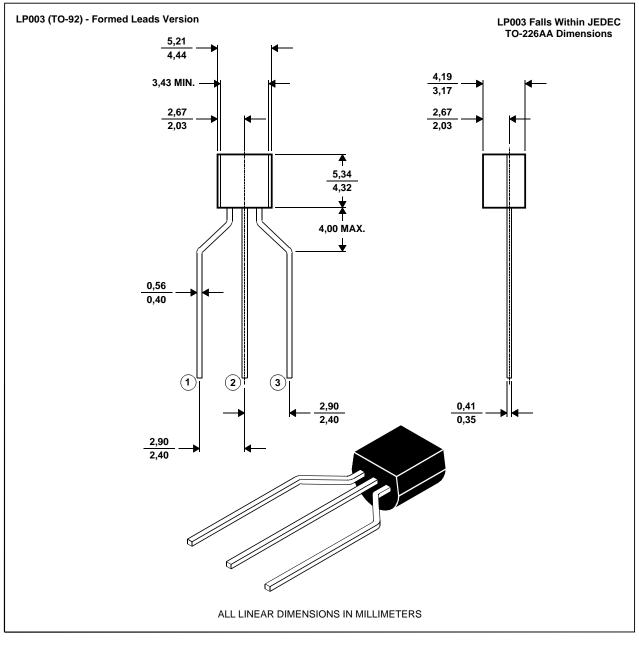
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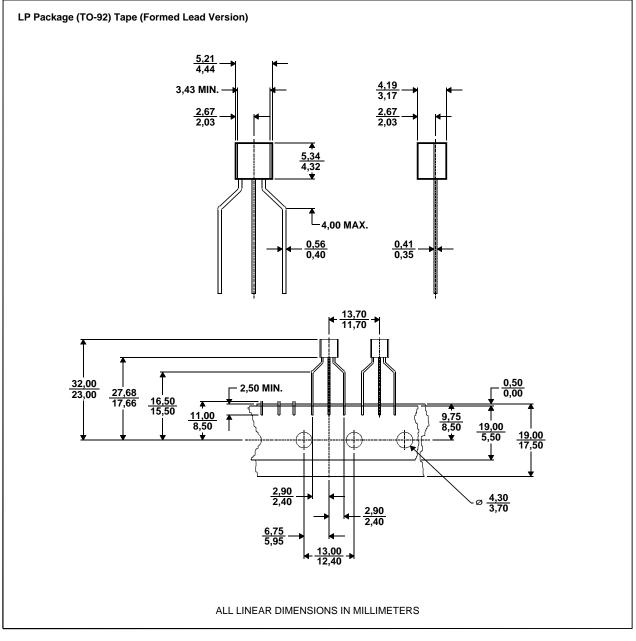


MDXXAR

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MECHANICAL DATA

LPR tape dimensions



MDXXAS



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